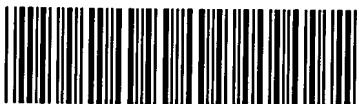


Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/656,199	NAKATA ET AL.	
Examiner	Art Unit	
Phat X. Cao	2814	

SEARCHED

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

INTERFERENCE SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner